

SXNS17

Monday, 15 July 2024

Instrumentation and methods I: Instrumentation and methods I (16:20 - 18:10)

-Conveners: Tom Arnold

time	[id] title	presenter
16:20	[99] Reinventing lost art in reflectometry – as illustrated by polymer brushes	Dr NELSON, Andrew
16:50	[78] ML-based online analysis and autonomous closed-loop experiments at synchrotron beamlines: A case study in x-ray reflectometry	STAROSTIN, Vladimir
17:10	[81] The ESTIA beamline at ESS - a new paradigm for neutron reflectometry	COOPER, Joshaniel
17:30	[68] Local atomic structure of highly ordered and highly disordered thin films: recent advances of in situ grazing incidence total x-ray scattering	DIPPEL, Ann-Christin Mr GUTOWSKI, Olof Dr ZIMMERMANN, Martin v.
17:50	[9] Development of neutron reflectometry tomography and its application to polymer interfaces	AOKI, Hiroyuki